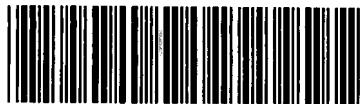


Search Notes

Application/Control No.

10/602,810

Examiner

/BINH K. TIEU/

Applicant(s)/Patent under
Reexamination

AN

Art Unit

2614

SEARCHED			
Class	Subclass	Date	Examiner
455	410-411	8/5/2007	BKT
	414.1		
	557		
	566		
	550.1		
	412.2		
726	418-420		
	11		
	13		
	22		
	24		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST DATABASES SEARCH	8/5/2007	BKT
WEST DATABASES SEARCH	8/6/2007	BKT